

Search Notes**Application/Control No.**

10/600,853

Examiner

/Yonel Beaulieu/

**Applicant(s)/Patent under
Reexamination**

LICH ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
180	271	3/12/2008	YB
	282		
701	45-47		
340	425.5		
	435-436		
280	734-735		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR